Design For Test For Digital Ics And Embedded Core Systems

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MCMAHON ELIANNA

Design of Systems on a Chip: Design and Test Prentice Hall
This book presents the biophysics of hair. It covers the structure of hair, its mechanical properties, nanomechanical characterization, tensile deformation, tribological characterization, the thickness distribution and binding interactions on hair surface.
Simulation in the Design of Digital Electronic Systems Springer Science & Business Media
The modern electronic testing has a forty year history. Test professionals hold some fairly large conferences and numerous workshops, have a journal, and there are over one hundred books on testing. Still, a full course on testing is offered only at a few universities, mostly by professors who have a research interest in this area. Apparently, most professors would not have taken a course on electronic testing when they were students. Other than the computer engineering curriculum being too crowded, the major reason cited for the absence of a course on electronic testing is the lack of a suitable textbook. For VLSI the foundation was provided by semiconductor device techn- ogy, circuit design, and electronic testing. In a computer engineering curriculum, therefore, it is necessary that foundations should be taught before applications. The field of VLSI has expanded to systems-on-a-chip, which include digital, memory, and mixed-signalsubsystems. To our knowledge this is the first textbook to cover all three types of electronic circuits. We have written this textbook for an undergraduate “foundations” course on electronic testing. Obviously, it is too voluminous for a one-semester course and a teacher will have to select from the topics. We did not restrict such freedom because the selection may depend upon the individual expertise and interests. Besides, there is merit in having a larger book that will retain its usefulness for the owner even after the completion of the course. With equal tenacity, we address the needs of three other groups of readers.
A Guide to DFT and Other Techniques CRC Press
From the reviews: "[...] a welcome addition to the literature. [...] This book promises to make a valuable contribution to the education of graduate students in electrical and computer engineering, and a very useful addition to the library of the maturer investigator in SoC designs or related fields." Microelectronics Reliability
Computational Intelligence in Digital and Network Designs and Applications Springer Science & Business Media
This book is about digital system testing and testable design. The concepts of testing and testability are treated together with digital design practices and methodologies. The book uses Verilog models and testbenches for implementing and explaining fault simulation and test generation algorithms. Extensive use of Verilog and Verilog PLI for test applications is what distinguishes this book from other test and testability books. Verilog eliminates ambiguities in test algorithms and BIST and DFT hardware architectures, and it clearly describes the architecture of the testability hardware and its test sessions. Describing many of the on-chip decompression algorithms in Verilog helps to evaluate these algorithms in terms of hardware overhead and timing, and thus feasibility of using them for System-on-Chip designs. Extensive use of testbenches and testbench development techniques is another unique feature of this book. Using PLI in developing testbenches and virtual testers provides a powerful programming tool, interfaced with hardware described in Verilog. This mixed hardware/software environment facilitates description of complex test programs and test strategies.
Digital Integrated Circuits Springer Science & Business Media
"Introduces a theory of random testing in digital circuits for the first time and offers practical guidance for the implementation of random pattern generators, signature analyzers design for random testability, and testing results. Contains several new and unpublished results. "
Digital Circuit Testing CRC Press
Your road map for meeting today's digital testing challenges Today, digital logic devices are common in products that impact public safety, including applications in transportation and human implants. Accurate testing has become more critical to reliability, safety, and the bottom line. Yet, as digital systems become more ubiquitous and complex, the challenge of testing them has become more difficult. As one development group designing a RISC stated, "the work required to . . . test a chip of this size approached the amount of effort required to design it." A valued reference for nearly two decades, Digital Logic Testing and Simulation has been significantly revised and updated for designers and test engineers who must meet this challenge. There is no single solution to the testing problem. Organized in an easy-to-follow, sequential format, this Second Edition familiarizes the reader with the many different strategies for testing and their applications, and assesses the strengths and weaknesses of the various approaches. The book reviews the building blocks of a successful testing strategy and guides the reader on choosing the best solution for a particular application. Digital Logic Testing and Simulation, Second Edition covers such key topics as: * Binary Decision Diagrams (BDDs) and cycle-based simulation * Tester architectures/Standard Test Interface Language (STIL) * Practical algorithms written in a Hardware Design Language (HDL) * Fault tolerance * Behavioral Automatic Test Pattern Generation (ATPG) * The development of the Test Design Expert (TDX), the many obstacles encountered and lessons learned in creating this novel testing approach Up-to-date and comprehensive, Digital Logic Testing and Simulation is an important resource for anyone charged with pinpointing faulty

products and assuring quality, safety, and profitability.

Digital Logic Testing and Simulation Springer

This book is a self-contained introduction to all aspects of microelectronic (IC) testing. It includes the theory necessary for advanced students as well as reference to industrial practice and economics that will interest designers in industry. Chapters cover both digital circuit testing and the growing area of mixed circuits, used particularly in signal processing.

IET

The first of two volumes in the Electronic Design Automation for Integrated Circuits Handbook, Second Edition, Electronic Design Automation for IC System Design, Verification, and Testing thoroughly examines system-level design, microarchitectural design, logic verification, and testing. Chapters contributed by leading experts authoritatively discuss processor modeling and design tools, using performance metrics to select microprocessor cores for integrated circuit (IC) designs, design and verification languages, digital simulation, hardware acceleration and emulation, and much more. New to This Edition: Major updates appearing in the initial phases of the design flow, where the level of abstraction keeps rising to support more functionality with lower non-recurring engineering (NRE) costs Significant revisions reflected in the final phases of the design flow, where the complexity due to smaller and smaller geometries is compounded by the slow progress of shorter wavelength lithography New coverage of cutting-edge applications and approaches realized in the decade since publication of the previous edition—these are illustrated by new chapters on high-level synthesis, system-on-chip (SoC) block-based design, and back-annotating system-level models Offering improved depth and modernity, Electronic Design Automation for IC System Design, Verification, and Testing provides a valuable, state-of-the-art reference for electronic design automation (EDA) students, researchers, and professionals.

Digital Circuit Testing and Testability Morgan Kaufmann

Today's computers must perform with increasing reliability, which in turn depends onthe problem of determining whether a circuit has been manufactured properly or behaves correctly.However, the greater circuit density of VLSI circuits and systems has made testing more difficultand costly. This book notes that one solution is to develop faster and more efficient algorithms togenerate test patterns or use design techniques to enhance testability - that is, "design fortestability." Design for testability techniques offer one approach toward alleviating this situationby adding enough extra circuitry to a circuit or chip to reduce the complexity of testing. Becausethe cost of hardware is decreasing as the cost of testing rises, there is now a growing interest inthese techniques for VLSI circuits.The first half of the book focuses on the problem of testing:test generation, fault simulation, and complexity of testing. The second half takes up the problemof design for testability: design techniques to minimize test application and/or test generationcost, scan design for sequential logic circuits, compact testing, built-in testing, and variousdesign techniques for testable systems.Hideo Fujiwara is an associate professor in the Department ofElectronics and Communication, Meiji University. Logic Testing and Design for Testability isincluded in the Computer Systems Series, edited by Herb Schwetman.

Design of High Speed Interconnects and Signaling MIT Press (MA)

Digital System Test and Testable DesignUsing HDL Models and ArchitecturesSpringer Science & Business Media

VLSI Test Principles and Architectures Springer Science & Business Media

High Speed Digital Design discusses the major factors to consider in designing a high speed digital system and how design concepts affect the functionality of the system as a whole. It will help you understand why signals act so differently on a high speed digital system, identify the various problems that may occur in the design, and research solutions to minimize their impact and address their root causes. The authors offer a strong foundation that will help you get high speed digital system designs right the first time. Taking a systems design approach, High Speed Digital Design offers a progression from fundamental to advanced concepts, starting with transmission line theory, covering core concepts as well as recent developments. It then covers the challenges of signal and power integrity, offers guidelines for channel modeling, and optimizing link circuits. Tying together concepts presented throughout the book, the authors present Intel processors and chipsets as real-world design examples. Provides knowledge and guidance in the design of high speed digital circuits Explores the latest developments in system design Covers everything that encompasses a successful printed circuit board (PCB) product Offers insight from Intel insiders about real-world high speed digital design

High Speed Digital Design Elsevier

This book is a comprehensive guide to new DFT methods that will show the readers how to design a testable and quality product, drive down test cost, improve product quality and yield, and speed up time-to-market and time-to-volume. Most up-to-date coverage of design for testability. Coverage of industry practices commonly found in commercial DFT tools but not discussed in other books. Numerous, practical examples in each chapter illustrating basic VLSI test principles and DFT architectures.

Design and Test of Digital Circuits by Quantum-dot Cellular Automata CRC Press

This book provides a comprehensive methodology for automated design, test and diagnosis, and use of robust, low-cost, and manufacturable digital microfluidic systems. It focuses on the development of a comprehensive CAD optimization framework for digital microfluidic biochips that unifies different design problems. With the increase in system complexity and integration levels, biochip designers can utilize the design methods described in this book to evaluate different design alternatives, and carry out design-space exploration to obtain the best design point.

Nanometer Design for Testability Springer Science & Business Media

This book describes innovative techniques to address the testing needs of 3D stacked integrated circuits (ICs) that utilize through-silicon-vias (TSVs) as vertical interconnects. The authors identify the key challenges facing 3D IC testing and present results that have emerged from cutting-edge research in this domain. Coverage includes topics ranging from die-level wrappers, self-test circuits, and TSV probing to test-architecture design, test scheduling, and optimization. Readers will benefit from an in-depth look at test-technology solutions that are needed to make 3D ICs a reality and commercially viable.

Digital Integrated Circuits Springer Science & Business Media

This book will introduce design methodologies, known as Built-in-Self-Test (BiST) and Built-in-Self-Calibration (BiSC), which enhance the robustness of radio frequency (RF) and millimeter wave (mmWave) integrated circuits (ICs). These circuits are used in current and emerging communication, computing, multimedia and biomedical products and microchips. The design methodologies presented will result in enhancing the yield (percentage of working chips in a high volume run) of RF and mmWave ICs which will enable successful manufacturing of such microchips in high volume.

Design for Testability CRC Press

Test and Design-for-Testability in Mixed-Signal Integrated Circuits

deals with test and design for test of analog and mixed-signal integrated circuits. Especially in System-on-Chip (SoC), where different technologies are intertwined (analog, digital, sensors, RF); test is becoming a true bottleneck of present and future IC projects. Linking design and test in these heterogeneous systems will have a tremendous impact in terms of test time, cost and proficiency. Although it is recognized as a key issue for developing complex ICs, there is still a lack of structured references presenting the major topics in this area. The aim of this book is to present basic concepts and new ideas in a manner understandable for both professionals and students. Since this is an active research field, a comprehensive state-of-the-art overview is very valuable, introducing the main problems as well as the ways of solution that seem promising, emphasizing their basis, strengths and weaknesses. In essence, several topics are presented in detail. First of all, techniques for the efficient use of DSP-based test and CAD test tools. Standardization is another topic considered in the book, with focus on the IEEE 1149.4. Also addressed in depth is the connecting design and test by means of using high-level (behavioural) description techniques, specific examples are given. Another issue is related to test techniques for well-defined classes of integrated blocks, like data converters and phase-locked-loops. Besides these specification-driven testing techniques, fault-driven approaches are described as they offer potential solutions which are more similar to digital test methods. Finally, in Design-for-Testability and Built-In-Self-Test, two other concepts that were taken from digital design, are introduced in an analog context and illustrated for the case of integrated filters. In summary, the purpose of this book is to provide a glimpse on recent research results in the area of testing mixed-signal integrated circuits, specifically in the topics mentioned above. Much of the work reported herein has been performed within cooperative European Research Projects, in which the authors of the different chapters have actively collaborated. It is a representative snapshot of the current state-of-the-art in this emergent field.

Testing of Digital Systems Springer Science & Business Media

This textbook provides a comprehensive and detailed treatment of digital systems testing and testable design. It covers thoroughly both the fundamental concepts and the latest advances in this rapidly changing field, and presents only theoretical material that supports practical applications. Successfully used worldwide, this book is an invaluable tool for test engineers, ASIC and system designers, and CAD developers.

Digital and Mixed Analogue/digital Techniques Artech House Publishers

This book facilitates the VLSI-interested individuals with not only in-depth knowledge, but also the broad aspects of it by explaining its applications in different fields, including image processing and biomedical. The deep understanding of basic concepts gives you the power to develop a new application aspect, which is very well taken care of in this book by using simple language in explaining the concepts. In the VLSI world, the importance of hardware description languages cannot be ignored, as the designing of such dense and complex circuits is not possible without them. Both Verilog and VHDL languages are used here for designing. The current needs of high-performance integrated circuits (ICs) including low power devices and new emerging materials, which can play a very important role in achieving new functionalities, are the most interesting part of the book. The testing of VLSI circuits becomes more crucial than the designing of the circuits in this nanometer technology era. The role of fault simulation algorithms is very well explained, and its implementation using Verilog is the key aspect of this book. This book is well organized into 20 chapters. Chapter 1 emphasizes on uses of FPGA on various image processing and biomedical applications. Then, the descriptions enlighten the basic understanding of digital design from the perspective of HDL in Chapters 2–5. The performance enhancement with alternate material or geometry for silicon-based FET designs is focused in Chapters 6 and 7. Chapters 8 and 9 describe the study of bimolecular interactions with biosensing FETs. Chapters 10–13 deal with advanced FET structures available in various shapes, materials such as nanowire, HFET, and their comparison in terms of device performance metrics calculation. Chapters 14–18 describe different application-specific VLSI design techniques and challenges for analog and digital circuit designs. Chapter 19 explains the VLSI testability issues with the description of simulation and its categorization into logic and fault simulation for test pattern generation using Verilog HDL. Chapter 20 deals with a secured VLSI design with hardware obfuscation by hiding the IC’s structure and function, which makes it much more difficult to reverse engineer.

Design-for-Test and Test Optimization Techniques for TSV-based 3D Stacked ICs Springer Science & Business Media

Using the book and the software provided with it, the reader can build his/her own tester arrangement to investigate key aspects of analog-, digital- and mixed system circuits Plan of attack based on traditional testing, circuit design and circuit manufacture allows the reader to appreciate a testing regime from the point of view of all the participating interests Worked examples based on theoretical bookwork, practical experimentation and simulation exercises teach the reader how to test circuits thoroughly and effectively

Using HDL Models and Architectures Cambridge University Press

This book introduces several novel approaches to pave the way for the next generation of integrated circuits, which can be successfully and reliably integrated, even in safety-critical applications. The authors describe new measures to address the rising challenges in the field of design for testability, debug, and reliability, as strictly required for state-of-the-art circuit designs. In particular, this book combines formal techniques, such as the Satisfiability (SAT) problem and the Bounded Model Checking (BMC), to address the arising challenges concerning the increase in test data volume, as well as test application time and the required reliability. All methods are discussed in detail and evaluated extensively, while considering industry-relevant benchmark candidates. All measures have been integrated into a common framework, which implements standardized software/hardware interfaces.